

Search Notes**Application/Control No.**

10/689,091

**Applicant(s)/Patent under
Reexamination**

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Examiner

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Art Unit

2166

SEARCHED

Class	Subclass	Date	Examiner
707	10,13,104, 1,100,101	5/31/2006	LJH

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR